

**FEATURES**

- 25, 45 ns Read Access & R/W Cycle Times
- Unlimited Read/Write Endurance
- Automatic Non-Volatile *STORE* on Power Loss
- Non-Volatile *STORE* Under Hardware Control
- Automatic *RECALL* to SRAM on Power Up
- Unlimited *RECALL* Cycles
- 1 Million *STORE* Cycles
- 100-Year Non-volatile Data Retention
- Single 5.0V  $\pm 10\%$  Operation
- Commercial, Industrial, and Military Temperatures
- 28-Pin 300 mil SOIC or 330 mil SOIC (RoHS-Compliant)

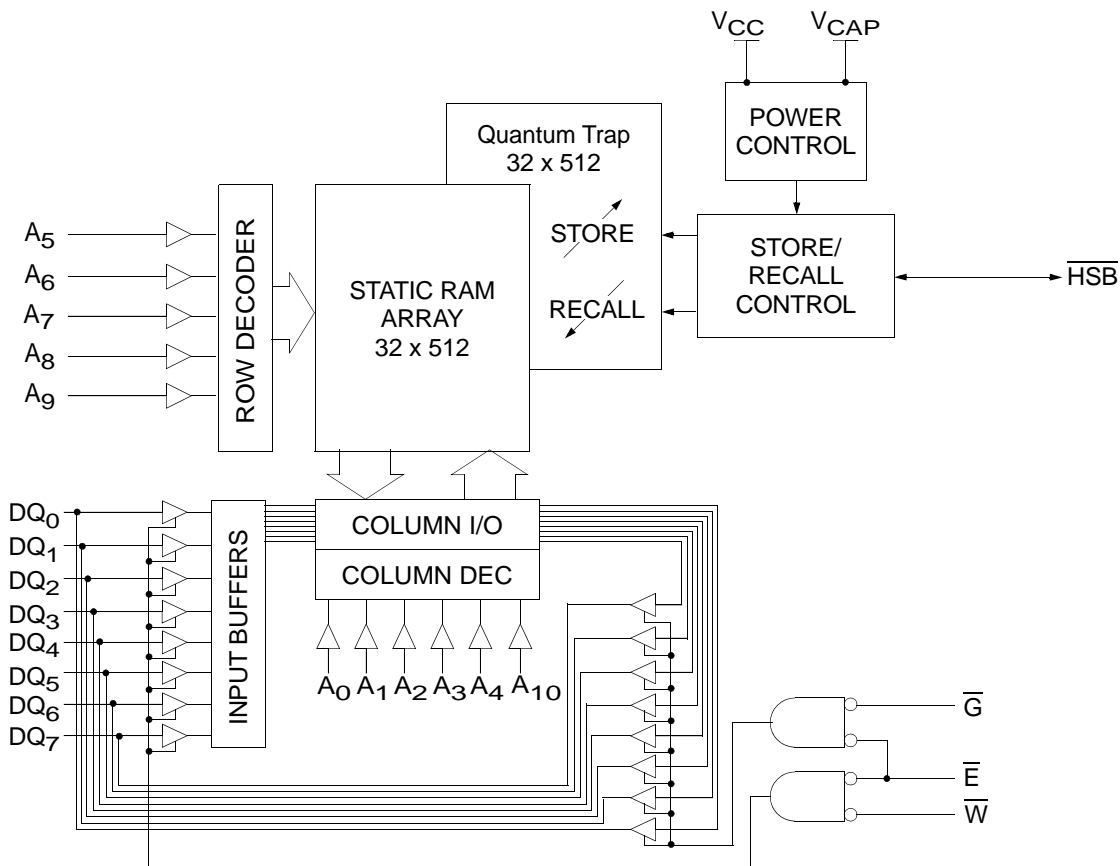
**DESCRIPTION**

The Simtek STK22C48 is a 16Kb fast static RAM with a nonvolatile Quantum Trap storage element included with each memory cell.

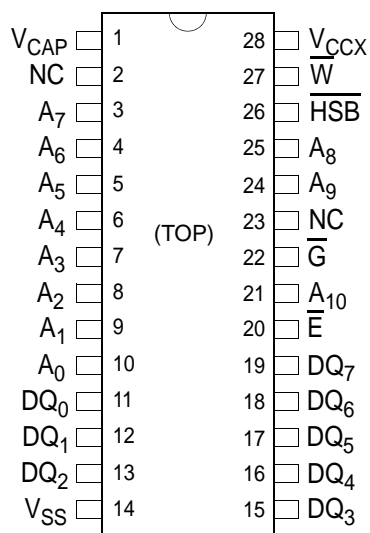
The SRAM provides the fast access & cycle times, ease of use, and unlimited read & write endurance of a normal SRAM.

Data transfers automatically to the non-volatile storage cells when power loss is detected (the *STORE* operation). On power-up, data is automatically restored to the SRAM (the *RECALL* operation). Both *STORE* and *RECALL* operations are also available under software control.

The Simtek nvSRAM is the first monolithic non-volatile memory to offer unlimited writes and reads. It is the highest-performance, most reliable non-volatile memory available.

**BLOCK DIAGRAM**


## PIN CONFIGURATIONS



28-pin 300 mil SOIC

28-pin 330 mil SOIC

## PIN DESCRIPTIONS

Pin Name	I/O	Description
A <sub>10</sub> -A <sub>0</sub>	Input	Address: The 11 address inputs select one of 2,048 bytes in the nvSRAM array
DQ <sub>7</sub> -DQ <sub>0</sub>	I/O	Data: Bi-directional 8-bit data bus for accessing the nvSRAM
Ē	Input	Chip Enable: The active low Ē input selects the device
W̄	Input	Write Enable: The active low W̄ enables data on the DQ pins to be written to the address location latched by the falling edge of Ē
Ḡ	Input	Output Enable: The active low Ḡ input enables the data output buffers during read cycles. De-asserting Ḡ high caused the DQ pins to tri-state.
V <sub>CC</sub>	Power Supply	Power: 5.0V, ±10%
V <sub>SS</sub>	Power Supply	Ground

**ABSOLUTE MAXIMUM RATINGS<sup>a</sup>**

Voltage on Input Relative to Ground	-0.5V to 7.0V
Voltage on Input Relative to V <sub>SS</sub>	-0.6V to (V <sub>CC</sub> + 0.5V)
Voltage on DQ <sub>0-7</sub> or HSB	-0.5V to (V <sub>CC</sub> + 0.5V)
Temperature under Bias	-55°C to 125°C
Storage Temperature	-65°C to 150°C
Power Dissipation	1W
DC Output Current (1 output at a time, 1s duration)	15mA

Note a: Stresses greater than those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. This is a stress rating only, and functional operation of the device at conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

Package Thermal Characteristics - See Website at <http://www.simtek.com>

**DC CHARACTERISTICS**

(V<sub>CC</sub> = 5.0V ± 10%)<sup>e</sup>

SYMBOL	PARAMETER	COMMERCIAL		INDUSTRIAL		UNITS	NOTES
		MIN	MAX	MIN	MAX		
I <sub>CC1</sub> <sup>b</sup>	Average V <sub>CC</sub> Current		85		90	mA	t <sub>AVAV</sub> = 25ns t <sub>AVAV</sub> = 45ns
			65		65	mA	
I <sub>CC2</sub> <sup>c</sup>	Average V <sub>CC</sub> Current during STORE		3		3	mA	All Inputs Don't Care, V <sub>CC</sub> = max
I <sub>CC3</sub> <sup>b</sup>	Average V <sub>CC</sub> Current at t <sub>AVAV</sub> = 200ns 5V, 25°C, Typical		10		10	mA	$\bar{W} \geq (V_{CC} - 0.2V)$ All Others Cycling, CMOS Levels
I <sub>CC4</sub> <sup>c</sup>	Average V <sub>CAP</sub> Current during AutoStore Cycle		2		2	mA	All Inputs Don't Care
I <sub>SB1</sub> <sup>d</sup>	Average V <sub>CC</sub> Current (Standby, Cycling TTL Input Levels)		25		26	mA	t <sub>AVAV</sub> = 25ns, $\bar{E} \geq V_{IH}$ t <sub>AVAV</sub> = 45ns, $\bar{E} \geq V_{IH}$
			18		19	mA	
I <sub>SB2</sub> <sup>d</sup>	V <sub>CC</sub> Standby Current (Standby, Stable CMOS Input Levels)		1.5		1.5	mA	$\bar{E} \geq (V_{CC} - 0.2V)$ All Others V <sub>IN</sub> ≤ 0.2V or ≥ (V <sub>CC</sub> - 0.2V)
I <sub>ILK</sub>	Input Leakage Current		±1		±1	µA	V <sub>CC</sub> = max V <sub>IN</sub> = V <sub>SS</sub> to V <sub>CC</sub>
I <sub>OLK</sub>	Off-State Output Leakage Current		±5		±5	µA	V <sub>CC</sub> = max V <sub>IN</sub> = V <sub>SS</sub> to V <sub>CC</sub> , $\bar{E}$ or $\bar{G} \geq V_{IH}$
V <sub>IH</sub>	Input Logic “1” Voltage	2.2	V <sub>CC</sub> + .5	2.2	V <sub>CC</sub> + .5	V	All Inputs
V <sub>IL</sub>	Input Logic “0” Voltage	V <sub>SS</sub> - .5	0.8	V <sub>SS</sub> - .5	0.8	V	All Inputs
V <sub>OH</sub>	Output Logic “1” Voltage	2.4		2.4		V	I <sub>OUT</sub> = -4mA except HSB
V <sub>OL</sub>	Output Logic “0” Voltage		0.4		0.4	V	I <sub>OUT</sub> = 8mA except HSB
V <sub>BL</sub>	Logic “0” Voltage on HSB Output		0.4		0.4	V	I <sub>OUT</sub> = 3mA
T <sub>A</sub>	Operating Temperature	0	70	-40	85	°C	
V <sub>CAP</sub>	Storage Capacitance	61	220	61	220	µF	5 Volt rated, 68 µF+20%/-10% Nom.

Note b: I<sub>CC1</sub> and I<sub>CC3</sub> are dependent on output loading and cycle rate. The specified values are obtained with outputs unloaded.

Note c: I<sub>CC2</sub> and I<sub>CC4</sub> are the average currents required for the duration of the respective STORE cycles (t<sub>STORE</sub>).

Note d:  $\bar{E} \geq V_{IH}$  will not produce standby current levels until any nonvolatile cycle in progress has timed out.

Note e: V<sub>CC</sub> reference levels throughout this datasheet refer to V<sub>CC</sub> if that is where the power supply connection is made, or V<sub>CAP</sub> if V<sub>CC</sub> is connected to ground.

**AC TEST CONDITIONS**

Input Pulse Levels	.0V to 3V
Input Rise and Fall Times	≤ 5ns
Input and Output Timing Reference Levels	1.5V
Output Load	See Figure 1

**CAPACITANCE<sup>f</sup>** (T<sub>A</sub> = 25°C, f = 1.0MHz)

SYMBOL	PARAMETER	MAX	UNITS	CONDITIONS
C <sub>IN</sub>	Input Capacitance	8	pF	ΔV = 0 to 3V
C <sub>OUT</sub>	Output Capacitance	7	pF	ΔV = 0 to 3V

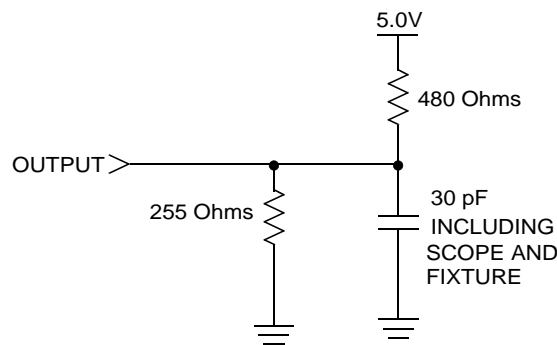


Figure 1: AC Output Loading

Note f: These parameters are guaranteed but not tested.

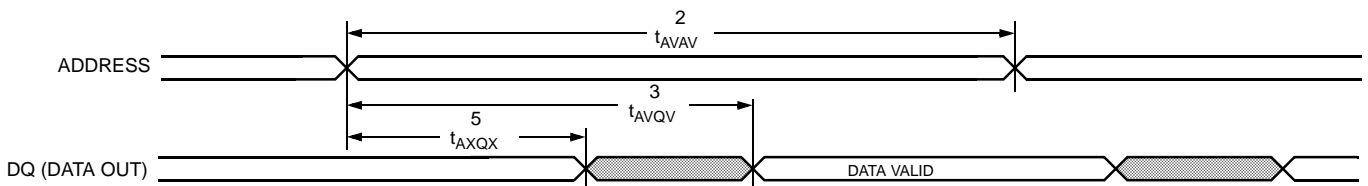
NO.	SYMBOLS		PARAMETER	STK22C48-25		STK22C48-45		UNITS
	#1, #2	Alt.		MIN	MAX	MIN	MAX	
1	t <sub>ELQV</sub>	t <sub>ACS</sub>	Chip Enable Access Time		25		45	ns
2	t <sub>AVAV</sub> <sup>g</sup> , t <sub>ELEH</sub> <sup>g</sup>	t <sub>RC</sub>	Read Cycle Time	25		45		ns
3	t <sub>AVQV</sub> <sup>h</sup>	t <sub>AA</sub>	Address Access Time		25		45	ns
4	t <sub>GLQV</sub>	t <sub>OE</sub>	Output Enable to Data Valid		10		20	ns
5	t <sub>AXQX</sub> <sup>h</sup>	t <sub>OH</sub>	Output Hold after Address Change	5		5		ns
6	t <sub>ELQX</sub>	t <sub>LZ</sub>	Address Change or Chip Enable to Output Active	5		5		ns
7	t <sub>EHQZ</sub> <sup>i</sup>	t <sub>HZ</sub>	Address Change or Chip Disable to Output Inactive		10		15	ns
8	t <sub>GLQX</sub>	t <sub>OLZ</sub>	Output Enable to Output Active	0		0		ns
9	t <sub>GHQZ</sub> <sup>i</sup>	t <sub>OHZ</sub>	Output Disable to Output Inactive		10		15	ns
10	t <sub>ELICCH</sub> <sup>f</sup>	t <sub>PA</sub>	Chip Enable to Power Active	0		0		ns
11	t <sub>EHICCL</sub> <sup>f</sup>	t <sub>PS</sub>	Chip Disable to Power Standby		25		45	ns

Note g:  $\bar{W}$  and  $\bar{HSB}$  must be high during SRAM READ cycles.

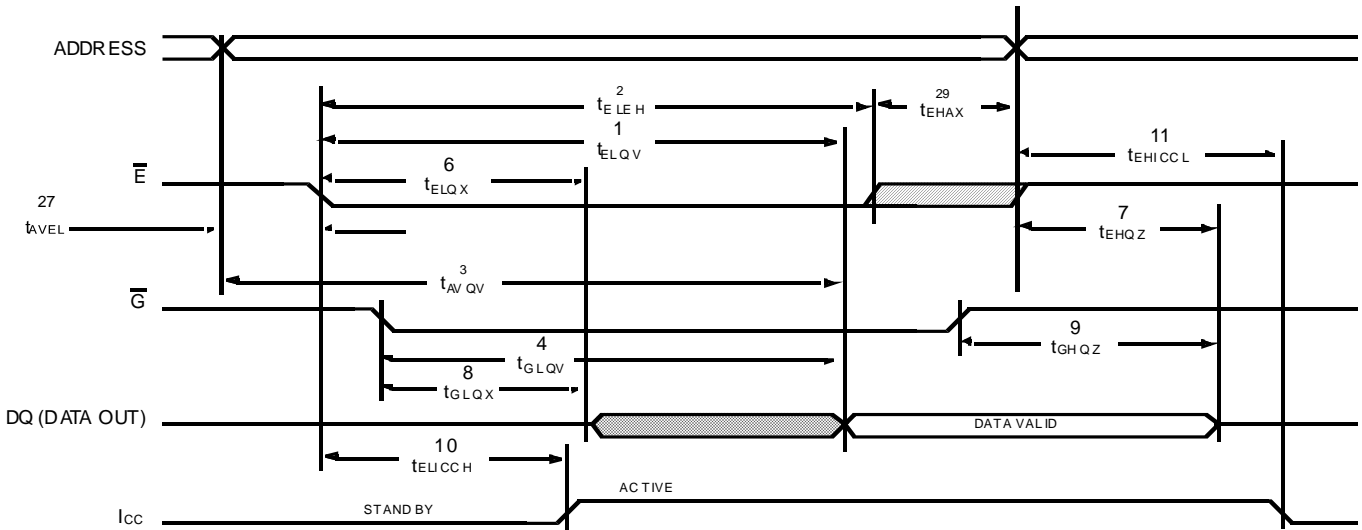
Note h: Device is continuously selected with  $\bar{E}$  and  $\bar{G}$  both low.

Note i: Measured ± 200mV from steady state output voltage.

### SRAM READ CYCLE #1: Address Controlled<sup>g, h</sup>



### SRAM READ CYCLE #2: $\bar{E}$ and $\bar{G}$ Controlled<sup>g</sup>



SRAM WRITE CYCLES #1 & #2

(V<sub>CC</sub> = 5.0V ± 10%)<sup>e</sup>

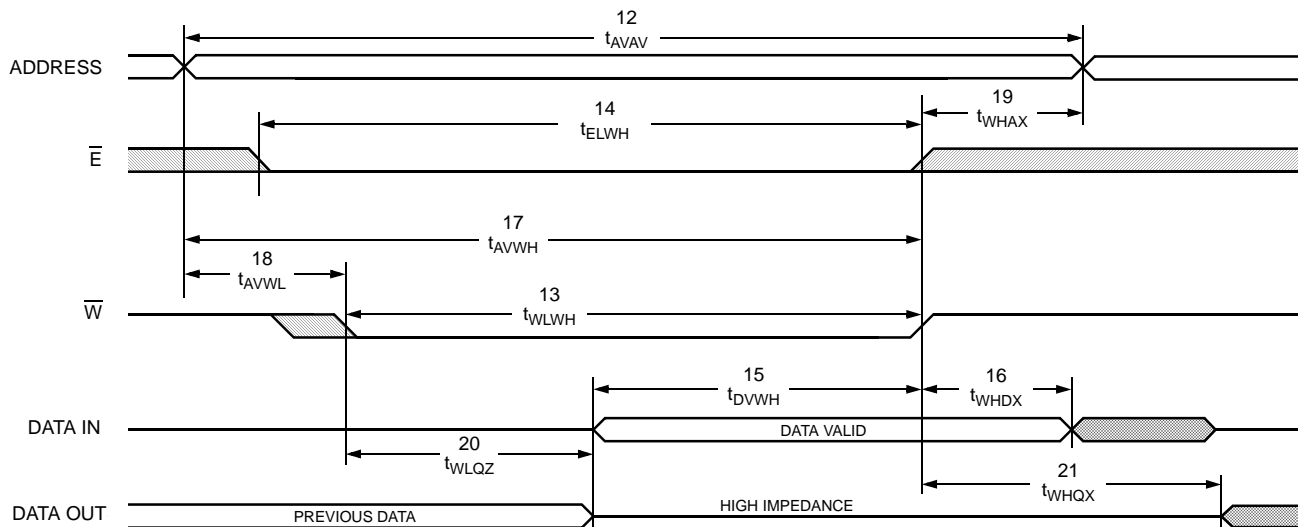
NO.	SYMBOLS			PARAMETER	STK22C48-25		STK22C48-45		UNITS
	#1	#2	Alt.		MIN	MAX	MIN	MAX	
12	t <sub>AVAV</sub>	t <sub>AVAV</sub>	t <sub>WC</sub>	Write Cycle Time	25		45		ns
13	t <sub>WLWH</sub>	t <sub>WLEH</sub>	t <sub>WP</sub>	Write Pulse Width	20		30		ns
14	t <sub>ELWH</sub>	t <sub>ELEH</sub>	t <sub>CW</sub>	Chip Enable to End of Write	20		30		ns
15	t <sub>DVWH</sub>	t <sub>DVEH</sub>	t <sub>DW</sub>	Data Set-up to End of Write	10		15		ns
16	t <sub>WHDX</sub>	t <sub>EHDX</sub>	t <sub>DH</sub>	Data Hold after End of Write	0		0		ns
17	t <sub>AVWH</sub>	t <sub>AVEH</sub>	t <sub>AW</sub>	Address Set-up to End of Write	20		30		ns
18	t <sub>AVWL</sub>	t <sub>AVEL</sub>	t <sub>AS</sub>	Address Set-up to Start of Write	0		0		ns
19	t <sub>WHAX</sub>	t <sub>EHAX</sub>	t <sub>WR</sub>	Address Hold after End of Write	0		0		ns
20	t <sub>WLQZ</sub> <sup>i, j</sup>		t <sub>WZ</sub>	Write Enable to Output Disable		10		15	ns
21	t <sub>WHQX</sub>		t <sub>OW</sub>	Output Active after End of Write	5		5		ns

Note j: If  $\overline{W}$  is low when  $\overline{E}$  goes low, the outputs remain in the high-impedance state.

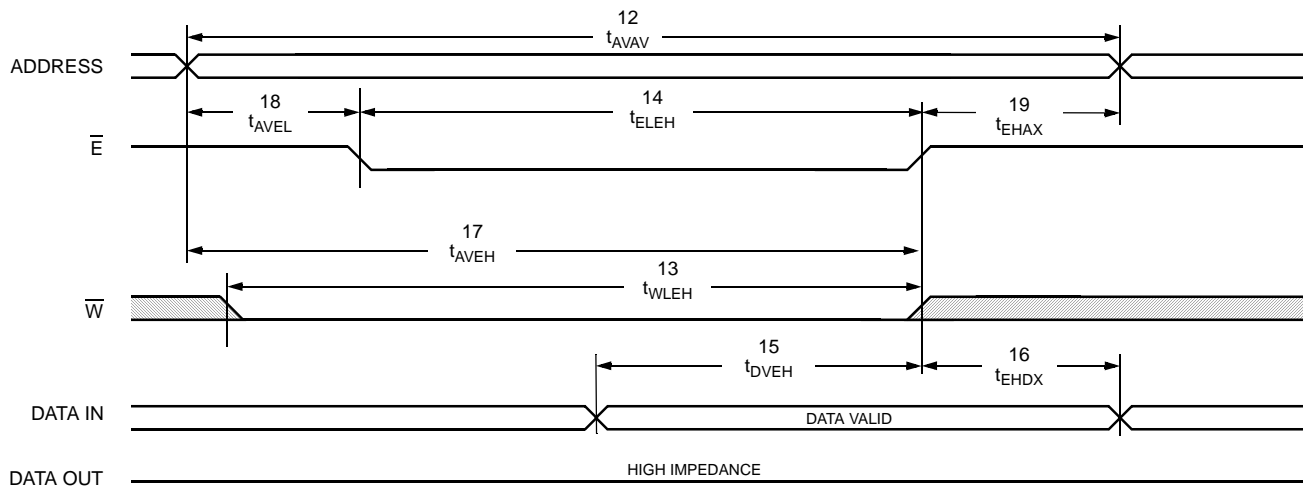
Note k:  $\overline{E}$  or  $\overline{W}$  must be  $\geq V_{IH}$  during address transitions.

Note l:  $\overline{HSB}$  must be high during SRAM WRITE cycles.

SRAM WRITE CYCLE #1:  $\overline{W}$  Controlled<sup>k, l</sup>



SRAM WRITE CYCLE #2:  $\overline{E}$  Controlled<sup>k, l</sup>



## HARDWARE MODE SELECTION

$\bar{E}$	$\bar{W}$	$\overline{HSB}$	A <sub>12</sub> - A <sub>0</sub> (hex)	MODE	I/O	POWER	NOTES
H	X	H	X	Not Selected	Output High Z	Standby	
L	H	H	X	Read SRAM	Output Data	Active	n
L	L	H	X	Write SRAM	Input Data	Active	
X	X	L	X	Nonvolatile STORE	Output High Z	I <sub>CC2</sub>	m

Note m:  $\overline{HSB}$  STORE operation occurs only if an SRAM write has been done since the last nonvolatile cycle. After the STORE (if any) completes, the part will go into standby mode, inhibiting all operations until  $\overline{HSB}$  rises.

Note n: I/O state assumes  $\bar{G} \leq V_{IL}$ . Activation of nonvolatile cycles does not depend on state of  $\bar{G}$ .

## HARDWARE STORE CYCLE

(V<sub>CC</sub> = 5.0V ± 10%)<sup>e</sup>

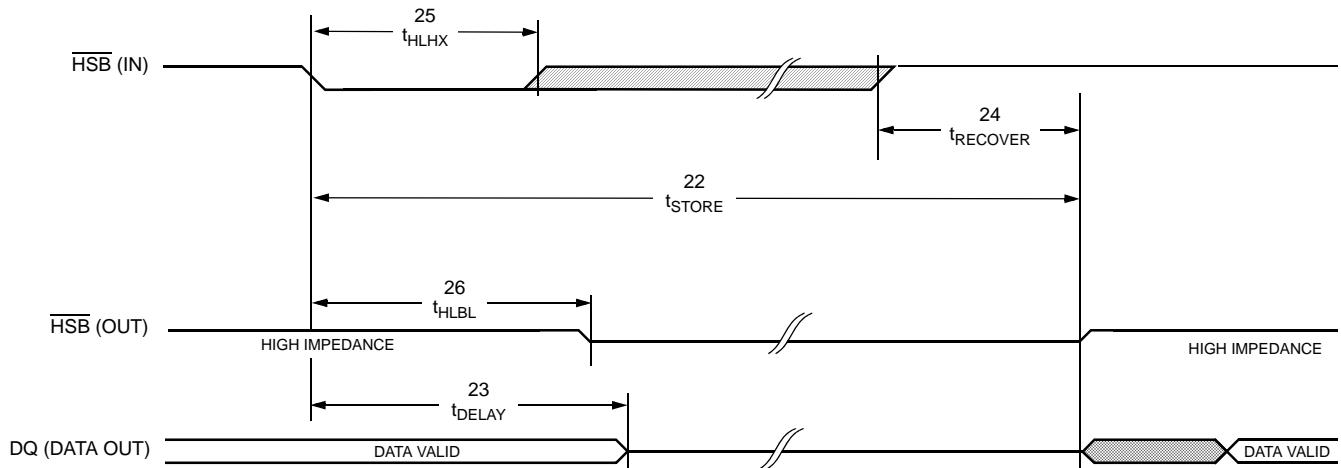
NO.	SYMBOLS		PARAMETER	STK22C48		UNITS	NOTES
	Standard	Alternate		MIN	MAX		
22	t <sub>STORE</sub>	t <sub>HLHZ</sub>	STORE Cycle Duration		10	ms	i, o
23	t <sub>DELAY</sub>	t <sub>HLQZ</sub>	Time Allowed to Complete SRAM Cycle	1		μs	i, p
24	t <sub>RECOVER</sub>	t <sub>HHQX</sub>	Hardware STORE High to Inhibit Off		700	ns	o, q
25	t <sub>HLHX</sub>		Hardware STORE Pulse Width	15		ns	
26	t <sub>HLBL</sub>		Hardware STORE Low to Store Busy		300	ns	

Note o:  $\bar{E}$  and  $\bar{G}$  low for output behavior.

Note p:  $\bar{E}$  and  $\bar{G}$  low and  $\bar{W}$  high for output behavior.

Note q: t<sub>RECOVER</sub> is only applicable after t<sub>STORE</sub> is complete.

## HARDWARE STORE CYCLE



**AutoStore™/POWER-UP RECALL**

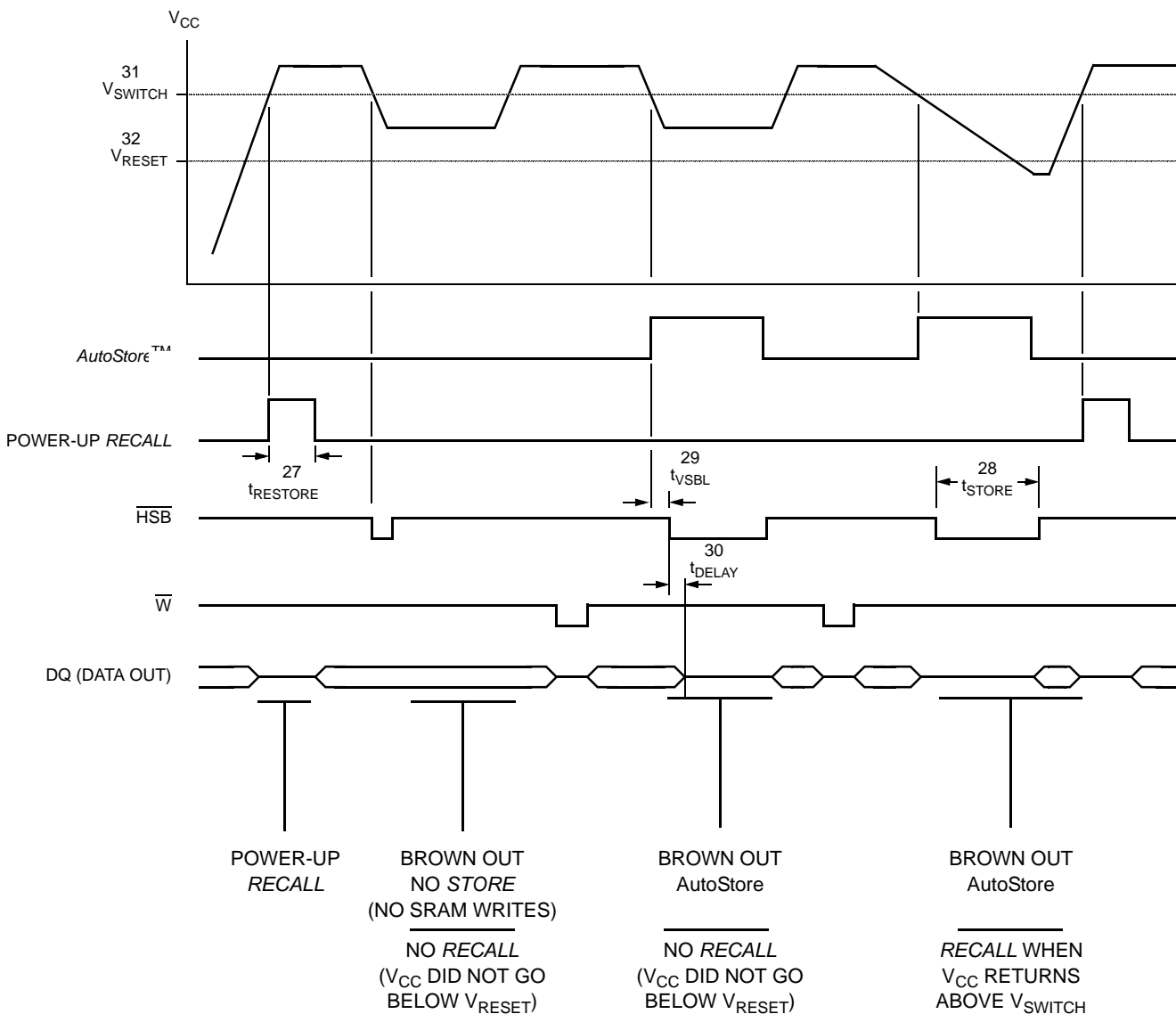
( $V_{CC} = 5.0V \pm 10\%$ )<sup>e</sup>

NO.	SYMBOLS		PARAMETER	STK22C48		UNITS	NOTES
	Standard	Alternate		MIN	MAX		
27	$t_{RESTORE}$		Power-up <i>RECALL</i> Duration		550	$\mu s$	r
28	$t_{STORE}$	$t_{HLHZ}$	<i>STORE</i> Cycle Duration		10	ms	p, s
29	$t_{VSBL}$		Low Voltage Trigger ( $V_{SWITCH}$ ) to $\overline{HSB}$ Low		300	ns	l
30	$t_{DELAY}$	$t_{BLQZ}$	Time Allowed to Complete SRAM Cycle	1		$\mu s$	o
31	$V_{SWITCH}$		Low Voltage Trigger Level	4.0	4.5	V	
32	$V_{RESET}$		Low Voltage Reset Level		3.6	V	

Note r:  $t_{RESTORE}$  starts from the time  $V_{CC}$  rises above  $V_{SWITCH}$ .

Note s:  $\overline{HSB}$  is asserted low for  $1\mu s$  when  $V_{CAP}$  drops through  $V_{SWITCH}$ . If an SRAM write has not taken place since the last nonvolatile cycle,  $\overline{HSB}$  will be released and no *STORE* will take place.

**AutoStore™/POWER-UP RECALL**



## nvSRAM OPERATION

The STK22C48 has two separate modes of operation: SRAM mode and nonvolatile mode. In SRAM mode, the memory operates as a standard fast static RAM. In nonvolatile mode, data is transferred from SRAM to Nonvolatile Elements (the *STORE* operation) or from Nonvolatile Elements to SRAM (the *RECALL* operation). In this mode SRAM functions are disabled.

### NOISE CONSIDERATIONS

The STK22C48 is a high-speed memory and so must have a high-frequency bypass capacitor of approximately 0.1μF connected between  $V_{CAP}$  and  $V_{SS}$ , using leads and traces that are as short as possible. As with all high-speed CMOS ICs, normal careful routing of power, ground and signals will help prevent noise problems.

### SRAM READ

The STK22C48 performs a *READ* cycle whenever  $\overline{E}$  and  $\overline{G}$  are low and  $\overline{W}$  and  $\overline{HSB}$  are high. The address specified on pins  $A_{0-10}$  determines which of the 2,048 data bytes will be accessed. When the *READ* is initiated by an address transition, the outputs will be valid after a delay of  $t_{AVQV}$  (*READ* cycle #1). If the *READ* is initiated by  $\overline{E}$  or  $\overline{G}$ , the outputs will be valid at  $t_{ELQV}$  or at  $t_{GLQV}$ , whichever is later (*READ* cycle #2). The data outputs will repeatedly respond to address changes within the  $t_{AVQV}$  access time without the need for transitions on any control input pins, and will remain valid until another address change or until  $\overline{E}$  or  $\overline{G}$  is brought high, or  $\overline{W}$  or  $\overline{HSB}$  is brought low.

### SRAM WRITE

A *WRITE* cycle is performed whenever  $\overline{E}$  and  $\overline{W}$  are low and  $\overline{HSB}$  is high. The address inputs must be stable prior to entering the *WRITE* cycle and must remain stable until either  $\overline{E}$  or  $\overline{W}$  goes high at the end of the cycle. The data on the common I/O pins  $DQ_{0-7}$  will be written into the memory if it is valid  $t_{DVWH}$  before the end of a  $\overline{W}$  controlled *WRITE* or  $t_{DVEH}$  before the end of an  $\overline{E}$  controlled *WRITE*.

It is recommended that  $\overline{G}$  be kept high during the entire *WRITE* cycle to avoid data bus contention on common I/O lines. If  $\overline{G}$  is left low, internal circuitry will turn off the output buffers  $t_{WLQZ}$  after  $\overline{W}$  goes low.

### POWER-UP RECALL

During power up, or after any low-power condition ( $V_{CAP} < V_{RESET}$ ), an internal *RECALL* request will be latched. When  $V_{CAP}$  once again exceeds the sense voltage of  $V_{SWITCH}$ , a *RECALL* cycle will automatically be initiated and will take  $t_{RESTORE}$  to complete.

If the STK22C48 is in a *WRITE* state at the end of power-up *RECALL*, the SRAM data will be corrupted. To help avoid this situation, a 10K Ohm resistor should be connected either between  $\overline{W}$  and system  $V_{CC}$  or between  $\overline{E}$  and system  $V_{CC}$ .

### AutoStore MODE

The STK22C48 can be powered in one of three modes.

During normal AutoStore operation, the STK22C48 will draw current from  $V_{CC}$  to charge a capacitor connected to the  $V_{CAP}$  pin. This stored charge will be used by the chip to perform a single *STORE* operation. After power up, when the voltage on the  $V_{CAP}$  pin drops below  $V_{SWITCH}$ , the part will automatically disconnect the  $V_{CAP}$  pin from  $V_{CC}$  and initiate a *STORE* operation.

Figure 2 shows the proper connection of capacitors for automatic store operation. A charge storage capacitor having a capacity of between 68μF and 220μF ( $\pm 20\%$ ) rated at 6V should be provided.

In system power mode, both  $V_{CC}$  and  $V_{CAP}$  are connected to the + 5V power supply without the 68μF capacitor. In this mode the AutoStore function of the

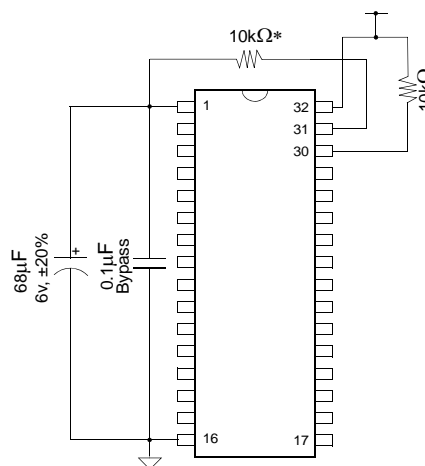


Figure 2: AutoStore Mode  
\*If  $\overline{HSB}$  is not used, it should be left unconnected.



STK22C48 will operate on the stored system charge as power goes down. The user must, however, guarantee that  $V_{CC}$  does not drop below 3.6V during the 10ms *STORE* cycle.

### AutoStore INHIBIT MODE

If an automatic *STORE* on power loss is not required, then  $V_{CC}$  can be tied to ground and + 5V applied to  $V_{CAP}$  (Figure 3). This is the AutoStore Inhibit mode, in which the AutoStore function is disabled. If the STK22C48 is operated in this configuration, references to  $V_{CC}$  should be changed to  $V_{CAP}$  throughout this data sheet. In this mode, *STORE* operations may be triggered with the  $\overline{HSB}$  pin. To enable or disable AutoStore using an IO port pin, see “PREVENTING STORES” on page 9.

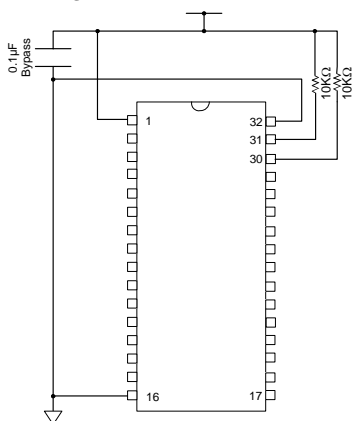


Figure 3: AutoStore Inhibit Mode

In order to prevent unneeded *STORE* operations, automatic *STOREs* as well as those initiated by externally driving  $\overline{HSB}$  low will be ignored unless at least one *WRITE* operation has taken place since the most recent *STORE* or *RECALL* cycle.

If the power supply drops faster than 20  $\mu$ s/volt before  $V_{CC}$  reaches  $V_{SWITCH}$ , then a 2.2 ohm resistor should be inserted between  $V_{CC}$  and the system supply to avoid momentary excess of current between  $V_{CC}$  and  $V_{cap}$ .

### $\overline{HSB}$ OPERATION

The STK22C48 provides the  $\overline{HSB}$  pin for controlling and acknowledging the *STORE* operations. The  $\overline{HSB}$  pin is used to request a hardware *STORE* cycle. When the  $\overline{HSB}$  pin is driven low, the STK22C48 will conditionally initiate a *STORE* operation after  $t_{DELAY}$ ; an actual *STORE* cycle will only begin if a *WRITE* to the SRAM took place since the last *STORE* or *RECALL* cycle. The  $\overline{HSB}$  pin has a very resistive pull-up and is internally driven low to indicate a busy

condition while the *STORE* (initiated by any means) is in progress. Pull up this pin with an external 10K ohm resistor to  $V_{CAP}$  if  $\overline{HSB}$  is used as a driver.

SRAM READ and WRITE operations that are in progress when  $\overline{HSB}$  is driven low by any means are given time to complete before the *STORE* operation is initiated. After  $\overline{HSB}$  goes low, the STK22C48 will continue SRAM operations for  $t_{DELAY}$ . During  $t_{DELAY}$ , multiple SRAM READ operations may take place. If a WRITE is in progress when  $\overline{HSB}$  is pulled low it will be allowed a time,  $t_{DELAY}$ , to complete. However, any SRAM WRITE cycles requested after  $\overline{HSB}$  goes low will be inhibited until  $\overline{HSB}$  returns high.

The  $\overline{HSB}$  pin can be used to synchronize multiple STK22C48s while using a single larger capacitor. To operate in this mode the  $\overline{HSB}$  pin should be connected together to the  $\overline{HSB}$  pins from the other STK22C48s. An external pull-up resistor to + 5V is required since  $\overline{HSB}$  acts as an open drain pull down. The  $V_{CAP}$  pins from the other STK22C48 parts can be tied together and share a single capacitor. The capacitor size must be scaled by the number of devices connected to it. When any one of the STK22C48s detects a power loss and asserts  $\overline{HSB}$ , the common  $\overline{HSB}$  pin will cause all parts to request a *STORE* cycle (a *STORE* will take place in those STK22C48s that have been written since the last nonvolatile cycle).

During any *STORE* operation, regardless of how it was initiated, the STK22C48 will continue to drive the  $\overline{HSB}$  pin low, releasing it only when the *STORE* is complete. Upon completion of the *STORE* operation the STK22C48 will remain disabled until the  $\overline{HSB}$  pin returns high.

If  $\overline{HSB}$  is not used, it should be left unconnected.

### PREVENTING STORES

The *STORE* function can be disabled on the fly by holding  $\overline{HSB}$  high with a driver capable of sourcing 30mA at a  $V_{OH}$  of at least 2.2V, as it will have to overpower the internal pull-down device that drives  $\overline{HSB}$  low for 20 $\mu$ s at the onset of a *STORE*. When the STK22C48 is connected for AutoStore operation (system  $V_{CC}$  connected to  $V_{CC}$  and a 68 $\mu$ F capacitor on  $V_{CAP}$ ) and  $V_{CC}$  crosses  $V_{SWITCH}$  on the way down, the STK22C48 will attempt to pull  $\overline{HSB}$  low; if  $\overline{HSB}$  doesn't actually get below  $V_{IL}$ , the part will stop trying to pull  $\overline{HSB}$  low and abort the *STORE* attempt.

## HARDWARE PROTECT

The STK22C48 offers hardware protection against inadvertent *STORE* operation and SRAM *WRITES* during low-voltage conditions. When  $V_{CAP} < V_{SWITCH}$ , all externally initiated *STORE* operations and SRAM *WRITES* are inhibited.

AutoStore can be completely disabled by tying  $V_{CCX}$  to ground and applying + 5V to  $V_{CAP}$ . This is the *AutoStore* Inhibit mode; in this mode *STOREs* are only initiated by explicit request using the *HSB* pin.

## LOW AVERAGE ACTIVE POWER

The STK22C48 draws significantly less current when it is cycled at times longer than 50ns. Figure 4

shows the relationship between  $I_{CC}$  and READ cycle time. Worst-case current consumption is shown for both CMOS and TTL input levels (commercial temperature range,  $V_{CC} = 5.5V$ , 100% duty cycle on chip enable). Figure 5 shows the same relationship for WRITE cycles. If the chip enable duty cycle is less than 100%, only standby current is drawn when the chip is disabled. The overall average current drawn by the STK22C48 depends on the following items: 1) CMOS vs. TTL input levels; 2) the duty cycle of chip enable; 3) the overall cycle rate for accesses; 4) the ratio of READs to WRITEs; 5) the operating temperature; 6) the  $V_{CC}$  level; and 7) I/O loading.

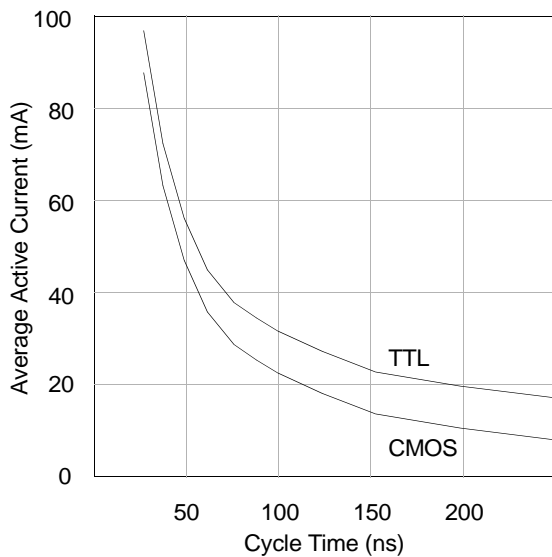


Figure 4:  $I_{CC}$  (max) Reads

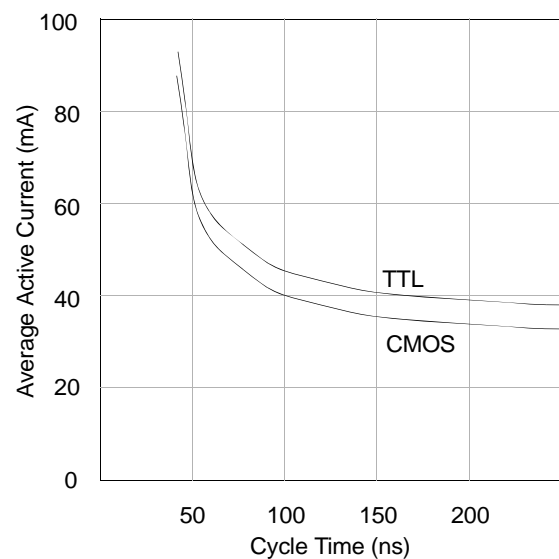


Figure 5:  $I_{CC}$  (max) Writes

## BEST PRACTICES

nvSRAM products have been used effectively for over 15 years. While ease-of-use is one of the product's main system values, experience gained working with hundreds of applications has resulted in the following suggestions as best practices:

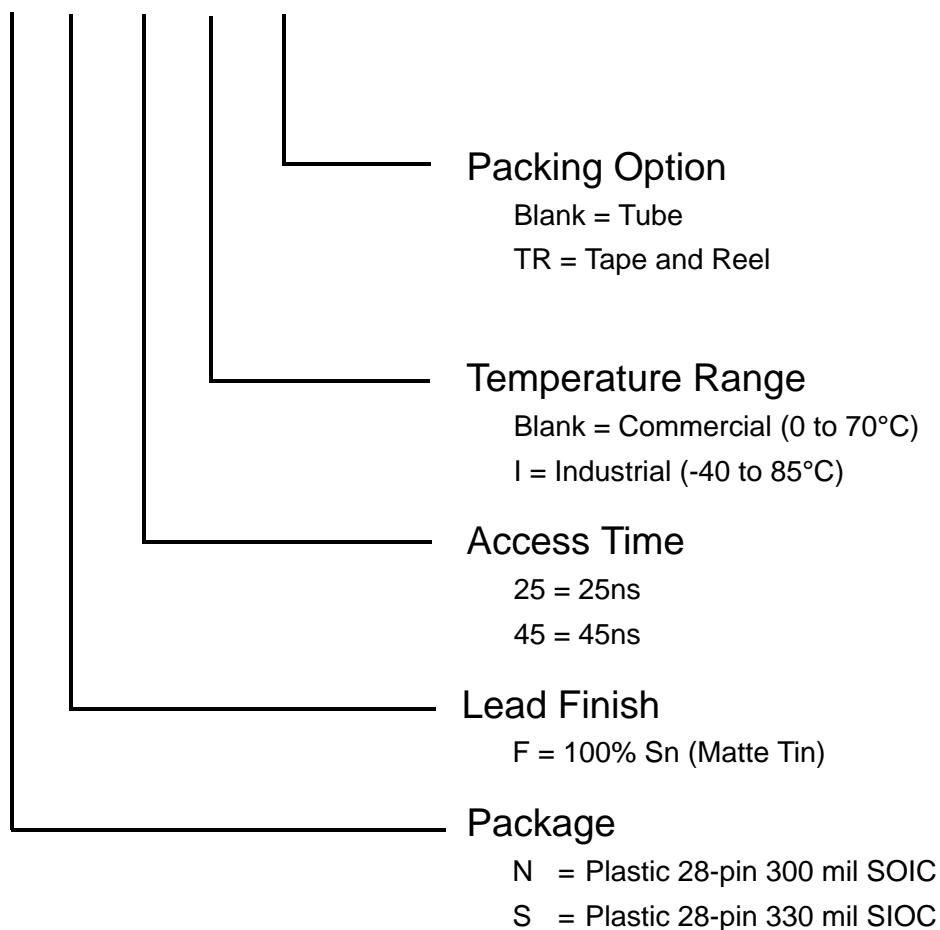
- The non-volatile cells in an nvSRAM are programmed on the test floor during final test and quality assurance. Incoming inspection routines at customer or contract manufacturer's sites will sometimes reprogram these values. Final NV patterns are typically repeating patterns of AA, 55, 00, FF, A5, or 5A. End product's firmware should not assume an NV array is in a set programmed state. Routines that check memory content values to determine first time system configuration, cold or warm boot status, etc. should always program a unique NV pattern (e.g., complex 4-byte pattern of 46 E6 49 53 hex or more random bytes) as part of the final system manufacturing test to ensure these system routines work consistently.
- Power up boot firmware routines should rewrite the nvSRAM into the desired state. While the nvSRAM is shipped in a preset state, best practice is to again rewrite the nvSRAM into the

desired state as a safeguard against events that might flip the bit inadvertently (program bugs, incoming inspection routines, etc.).

- The  $V_{cap}$  value specified in this datasheet includes a minimum and a maximum value size. Best practice is to meet this requirement and not exceed the max  $V_{cap}$  value because the higher inrush currents may reduce the reliability of the internal pass transistor. Customers that want to use a larger  $V_{cap}$  value to make sure there is extra store charge should discuss their  $V_{cap}$  size selection with Simtek.

## ORDERING INFORMATION

STK22C48 - N F 45 I TR

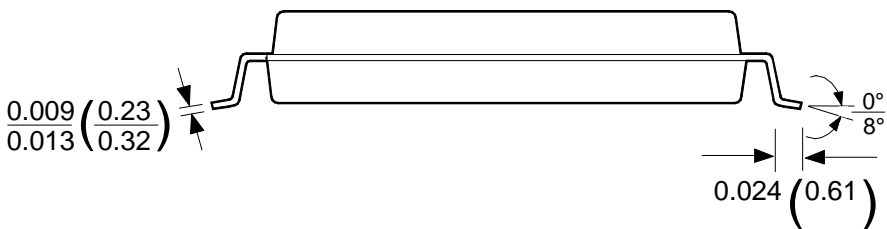
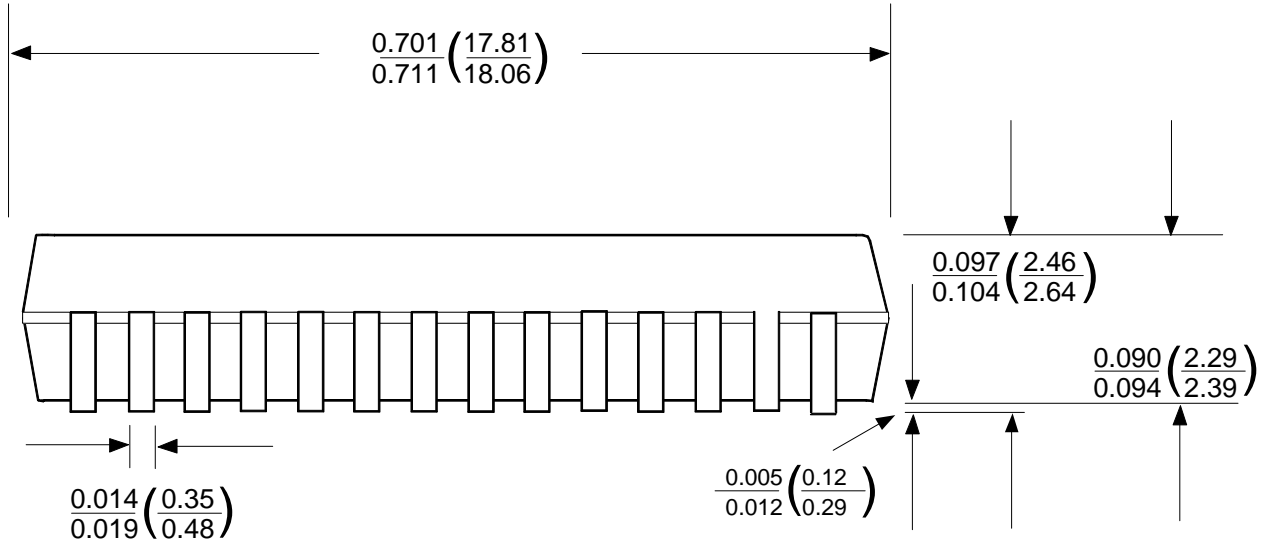
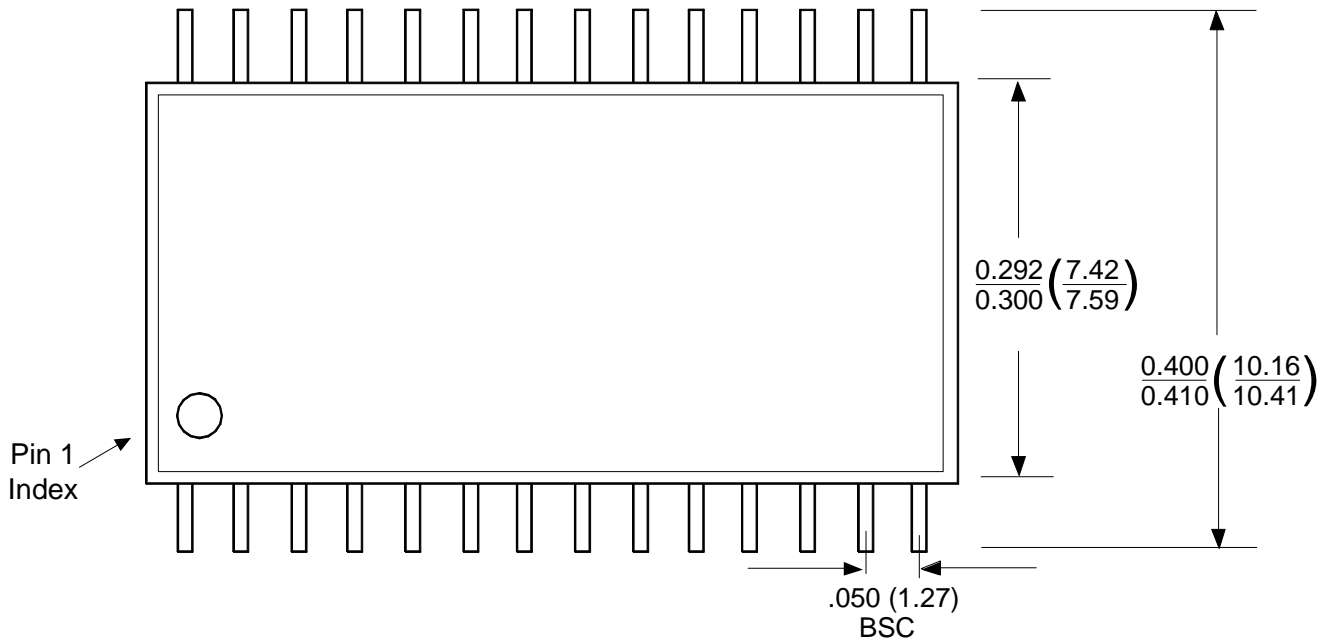


## Ordering Information

Item Number	Item Name	Access Times	Temperature
STK22C48-NF25	5V 2Kx 8 AutoStore nvSRAM SOP28-300	25 ns access time	Commercial
STK22C48-NF45	5V 2Kx 8 AutoStore nvSRAM SOP28-300	45 ns access time	Commercial
STK22C48-SF25	5V 2Kx 8 AutoStore nvSRAM SOP28-330	25 ns access time	Commercial
STK22C48-SF45	5V 2Kx 8 AutoStore nvSRAM SOP28-330	45 ns access time	Commercial
STK22C48-NF25TR	5V 2Kx 8 AutoStore nvSRAM SOP28-300	25 ns access time	Commercial
STK22C48-NF45TR	5V 2Kx 8 AutoStore nvSRAM SOP28-300	45 ns access time	Commercial
STK22C48-SF25TR	5V 2Kx 8 AutoStore nvSRAM SOP28-330	25 ns access time	Commercial
STK22C48-SF45TR	5V 2Kx 8 AutoStore nvSRAM SOP28-330	45 ns access time	Commercial
STK22C48-NF25I	5V 2Kx 8 AutoStore nvSRAM SOP28-300	25 ns access time	Industrial
STK22C48-NF45I	5V 2Kx 8 AutoStore nvSRAM SOP28-300	45 ns access time	Industrial
STK22C48-SF25I	5V 2Kx 8 AutoStore nvSRAM SOP28-330	25 ns access time	Industrial
STK22C48-SF45I	5V 2Kx 8 AutoStore nvSRAM SOP28-330	45 ns access time	Industrial
STK22C48-NF25ITR	5V 2Kx 8 AutoStore nvSRAM SOP28-300	25 ns access time	Industrial
STK22C48-NF45ITR	5V 2Kx 8 AutoStore nvSRAM SOP28-300	45 ns access time	Industrial
STK22C48-SF25ITR	5V 2Kx 8 AutoStore nvSRAM SOP28-330	25 ns access time	Industrial
STK22C48-SF45ITR	5V 2Kx 8 AutoStore nvSRAM SOP28-330	45 ns access time	Industrial

Package Diagrams

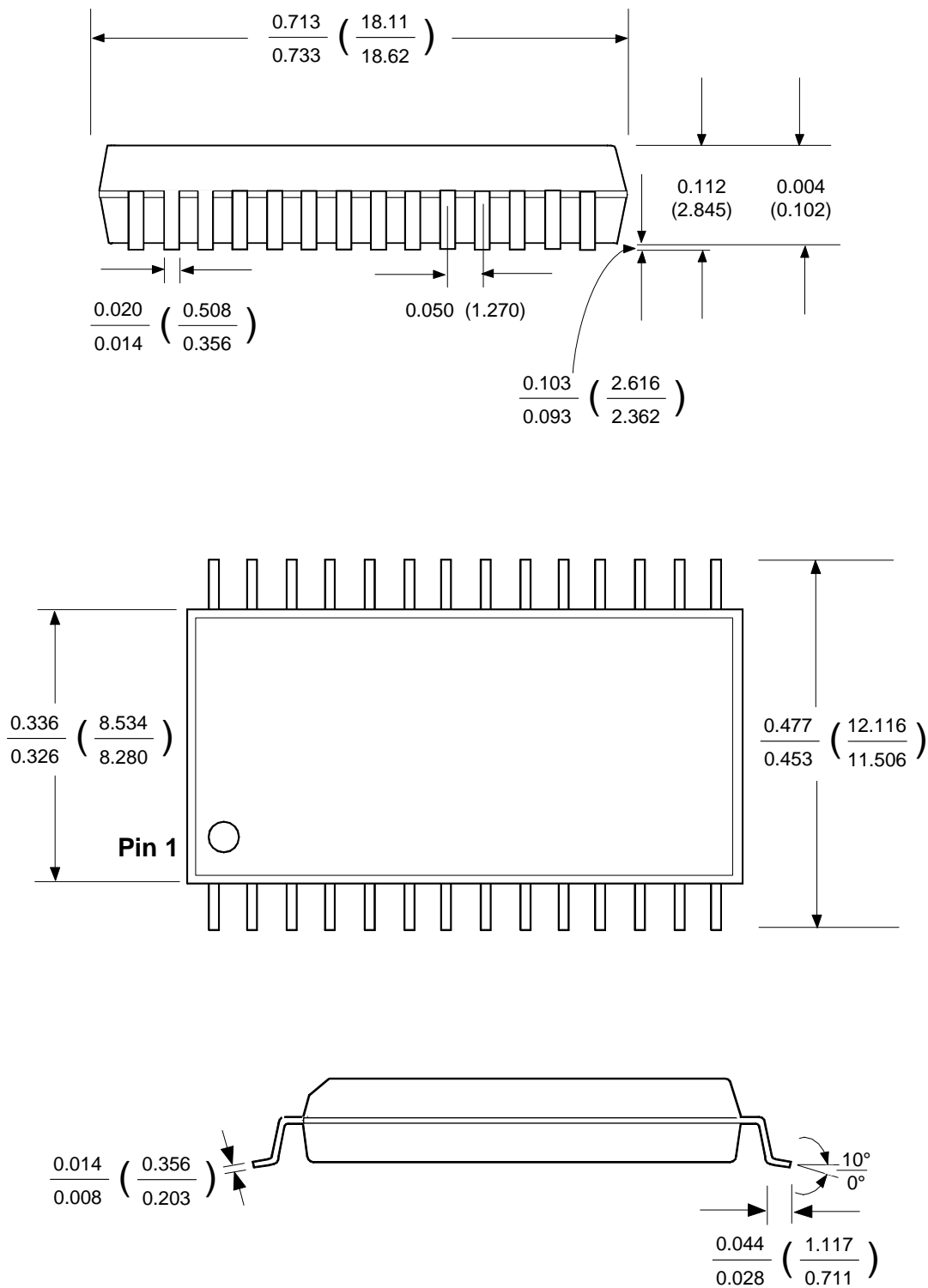
28-Lead, 300 mil SOIC Gull Wing



DIM = INCHES  $\frac{\text{MIN}}{\text{MAX}}$

DIM = mm  $\left( \frac{\text{MIN}}{\text{MAX}} \right)$

28-Lead, 330 mil SOIC Gull Wing



DIM = INCHES       $\frac{\text{MIN}}{\text{MAX}}$

DIM = mm       $\left( \frac{\text{MIN}}{\text{MAX}} \right)$

## Document Revision History

Revision	Date	Summary
0.0	December 2002	Removed 20 nsec device.
0.1	September 2003	Added lead-free lead finish
0.2	March 2006	Obsolete: 35ns speed grade, Plastic DIP packages and Leaded Lead Finish
0.3	February 2007	Add Fast Power-Down Slew Rate Information Add Tape Reel Ordering Options Add Product Ordering Code Listing Add Package Drawings Reformat Entire Document
2.0	January 2008	In the block diagram and elsewhere in this data sheet, removed the "x" from $V_{CCX}$ . Page 4: in SRAM Read Cycles #1 & #2 table, revised description for $t_{ELQX}$ and $t_{EHQZ}$ and changed Symbol #2 to $t_{ELEH}$ for Read Cycle Time. Page 4: updated SRAM Read Cycle #2 timing diagram and changed title to add $\bar{G}$ controlled. Page 9: under $\overline{HSB}$ Operation, revised first paragraph to read "The $\overline{HSB}$ pin has a very resistive pullup..." Page 11: added best practices section. Page 13: added access times to Ordering Information table.

SIMTEK STK22C48 Datasheet, January 2008

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